DMS935E1

Silicon NPN epitaxial planar type (Tr) Silicon epitaxial planar type (CCD load device)

For CCD output circuits

■ Features

- Two elements incorporated into one package (Tr + CCD load device)
- High transition frequency f_T
- Contributes to miniaturization of sets, reduction of component count.
- Eco-friendly Halogen-free package

■ Basic Part Number

DSC2G03 + CCD load device (Individual)

Packaging

Embossed type (Thermo-compression sealing): 8000 pcs / reel (standard)

■ Absolute Maximum Ratings $T_a = 25$ °C

	Parameter	Symbol	Rating	Unit
Tr1	Collector-base voltage (Emitter open)	V _{CBO}	30	V
	Collector-emitter voltage (Base open)	V _{CEO}	20	V
	Emitter-base voltage (Collector open)	V _{EBO}	3	V
	Collector current	I_{C}	50	mA
CCD	Limiting element voltage	V _{max}	40	V
load device	Limiting element current	I _{max}	10	mA
Overall	Total power dissipation *	P _T	125	mW
	Junction temperature	Tj	150	°C
	Storage temperature	T _{stg}	-55 to +150	°C

Note) *: Measuring on substrate at 17 mm \times 10 mm \times 1 mm

■ Electrical Characteristics $T_a = 25$ °C±3°C

• Tr1

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V _{CBO}	$I_C = 100 \mu A, I_E = 0$	30			V
Emitter-base voltage (Collector open)	V _{EBO}	$I_E = 10 \mu A, I_C = 0$	3			V
Base-emitter voltage	V _{BE}	$V_{CE} = 10 \text{ V}, I_{C} = 2 \text{ mA}$		740		mV
Forward current transfer ratio	h _{FE}	$V_{CE} = 10 \text{ V}, I_{C} = 2 \text{ mA}$	100		250	_
Transition frequency	f_T	$V_{CE} = 10 \text{ V}, I_{C} = 15 \text{ mA}$		1300		MHz

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

• CCD load device

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Pinchi off current	I_P	$V_{DS} = 10 V, V_G = 0$	3.8		5.2	mA
Output impedance	Z _O	$V_{DS} = 10 \text{ V}, V_G = 0$		0.05		μΩ

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

■ Package

Code

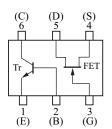
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• Pin Name

1: Emitter 4: Source 2: Base 5: Drain 3: Gate 6: Collector

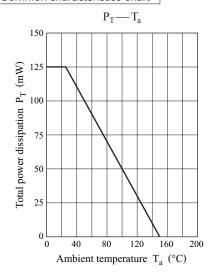
■ Marking Symbol: X0

■ Internal Connection

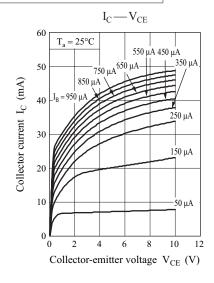


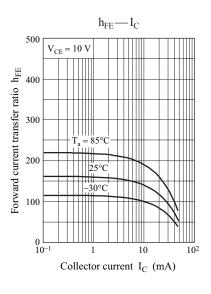
^{2. *:} Pulse measurement

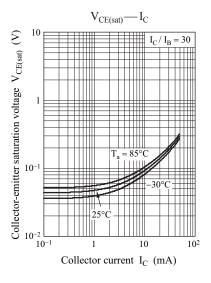
Common characteristics chart

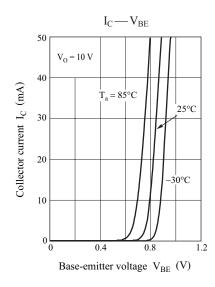


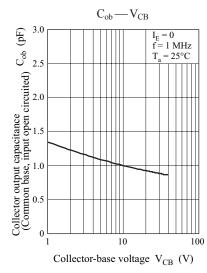
Characteristics charts of Tr

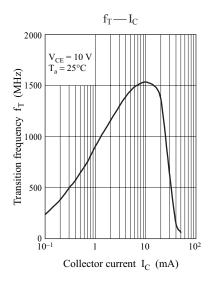






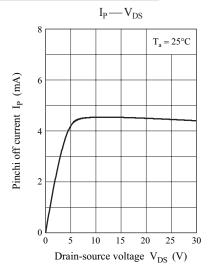






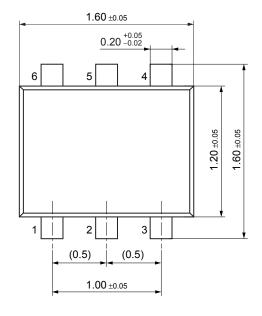
2 Ver. BED

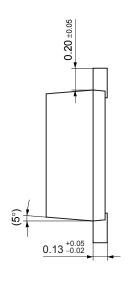
Characteristics charts of CCD

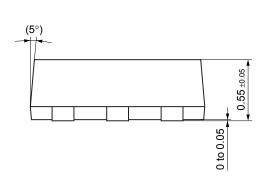


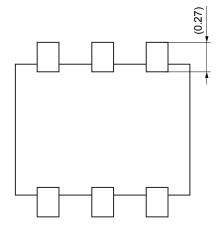
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Unit: mm









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